

December 2013

FCH041N60E N-Channel SuperFET[®] II Easy-Drive MOSFET 600 V, 77 A, 41 mΩ

Features

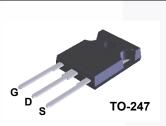
- 650 V @ T_J = 150°C
- Typ. R_{DS(on)} = 36 mΩ
- Ultra Low Gate Charge (Typ. Q_g = 285 nC)
- Low Effective Output Capacitance (Typ. Coss(eff.) = 735 pF)
- 100% Avalanche Tested
- · An Integrated Gate Resistor
- RoHS Compliant

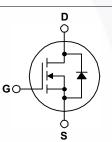
Applications

- LCD / LED / PDP TV Lighting
- Solar Inverter
- AC-DC Power Supply

Description

SuperFET[®] II MOSFET is Fairchild Semiconductor's brand-new high voltage super-junction (SJ) MOSFET family that is utilizing charge balance technology for outstanding low on-resistance and lower gate charge performance. This technology is tailored to minimize conduction loss, provide superior switching performance, dv/dt rate and higher avalanche energy. Consequently, SuperFET II MOSFET easy-drive series offers slightly slower rise and fall times compared to the SuperFET II MOSFET series. Noted by the "E" part number suffix, this family helps manage EMI issues and allows for easier design implementation. For faster switching in applications where switching losses must be at an absolute minimum, please consider the Super-FET II MOSFET series.





Absolute Maximum Ratings T_C = 25°C unless otherwise noted.

Symbol		Parameter		FCH041N60E	Unit	
V _{DSS}	Drain to Source Voltage			600	V	
V _{GSS}	Cata ta Cauraa Valtaga	- DC		±20	V	
	Gate to Source Voltage	- AC	(f > 1 Hz)	±30	- V	
ID	Drain Current	- Continuous (T _C = 25 ^o C)		77	A	
		- Continuous (T _C = 100 ^o C)		48.7		
I _{DM}	Drain Current	- Pulsed	(Note 1)	231	А	
E _{AS}	Single Pulsed Avalanche Energy (Note 2)		2025	mJ		
I _{AR}	Avalanche Current (Note 1)		15	Α		
E _{AR}	Repetitive Avalanche Energy (Note 1)		5.92	mJ		
dv/dt	MOSFET dv/dt			100	V/ns	
	Peak Diode Recovery dv/dt		(Note 3)	20	v/115	
P _D	Power Dissipation	(T _C = 25 ^o C)		592	W	
		- Derate Above 25°C		4.74	W/ºC	
T _J , T _{STG}	Operating and Storage Temperature Range			-55 to +150	°C	
TL	Maximum Lead Temperature for Soldering, 1/8" from Case for 5 Seconds			300	°C	

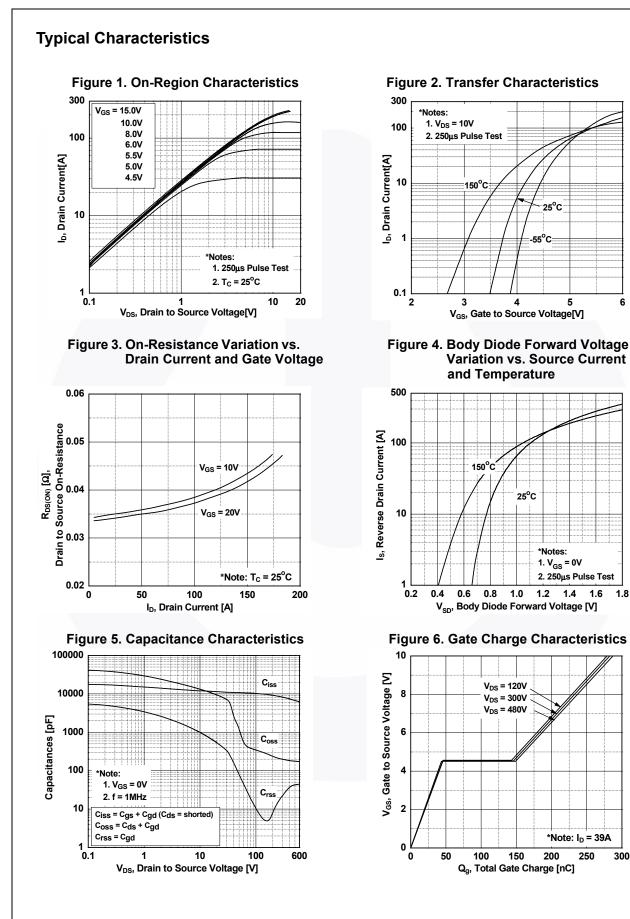
Thermal Characteristics

Symbol	Parameter	FCH041N60E	Unit	
$R_{ extsf{ heta}JC}$	Thermal Resistance, Junction to Case, Max.	0.21	°C/W	
$R_{ extsf{ heta}JA}$	Thermal Resistance, Junction to Ambient, Max.	40	- 'C/W	

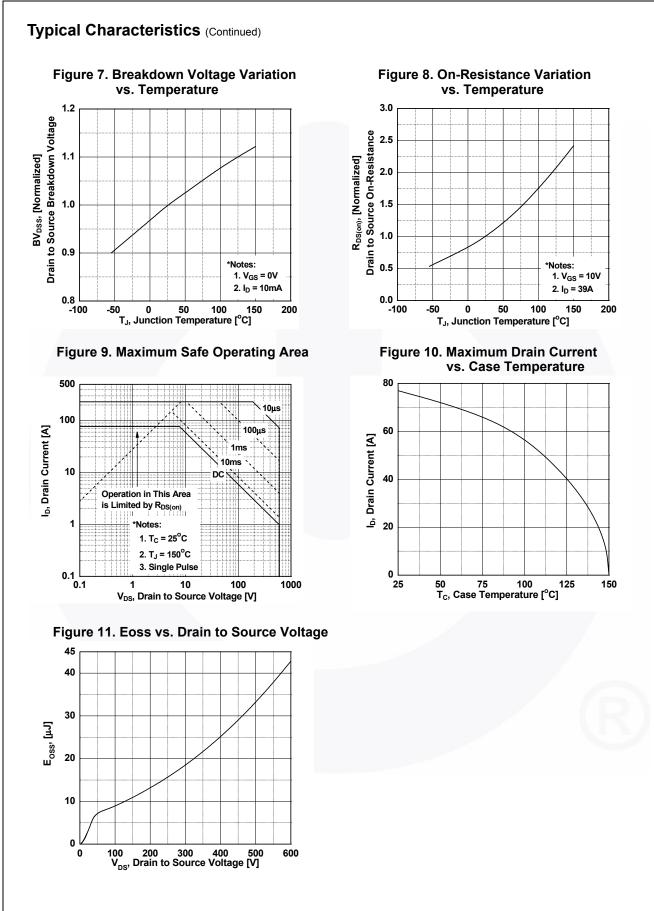
FCH041N60E Iracteristics T _C = 25°C Parameter Ics to Source Breakdown Voltage down Voltage Temperature cient Sate Voltage Drain Current o Body Leakage Current cs Threshold Voltage	$\frac{I_D = 1}{I_D = 1}$ $I_D = 1$ $I_D = 1$ $V_{DS} = V_{DS} = V_{DS} = 1$	Tube Test conditions 0 mA, $V_{GS} = 0 V$, $T_C = 0$ 0 mA, $V_{GS} = 0 V$, $T_C = 0$ 0 mA, Referenced to 25 480 V, $V_{GS} = 0 V$	150°C	Min. 600 650	N/A Typ.	Max.	30 units
Parameter CS to Source Breakdown Voltage down Voltage Temperature cient Gate Voltage Drain Current o Body Leakage Current CS	$\frac{I_D = 1}{I_D = 1}$ $I_D = 1$ $I_D = 1$ $V_{DS} = V_{DS} = V_{DS} = 1$	Test Conditions 0 mA, V_{GS} = 0 V, T_C = 0 mA, V_{GS} = 0 V, T_C = 0 mA, Referenced to 29	150°C	600	-	Max.	Unit
Parameter CS to Source Breakdown Voltage down Voltage Temperature cient Gate Voltage Drain Current o Body Leakage Current CS	$\frac{I_D = 1}{I_D = 1}$ $I_D = 1$ $I_D = 1$ $V_{DS} = V_{DS} = V_{DS} = 1$	Test Conditions 0 mA, V_{GS} = 0 V, T_C = 0 mA, V_{GS} = 0 V, T_C = 0 mA, Referenced to 29	150°C	600	-	Max.	Unit
to Source Breakdown Voltage down Voltage Temperature cient Gate Voltage Drain Current o Body Leakage Current CS	$\frac{I_{D} = 1}{I_{D} = 1}$ $\frac{I_{D} = 1}{V_{DS} = 1}$	0 mA, V _{GS} = 0 V, T _C = 0 mA, V _{GS} = 0 V, T _C = 0 mA, Referenced to 2	150°C	600	-	-	
to Source Breakdown Voltage down Voltage Temperature cient Gate Voltage Drain Current o Body Leakage Current CS	$\frac{I_{D} = 1}{I_{D} = 1}$ $\frac{I_{D} = 1}{V_{DS} = 1}$	0 mA, $V_{GS} = 0 V$, $T_C = 0$ mA, Referenced to 25	150°C			-	
down Voltage Temperature cient Gate Voltage Drain Current o Body Leakage Current CS	$\frac{I_{D} = 1}{I_{D} = 1}$ $\frac{I_{D} = 1}{V_{DS} = 1}$	0 mA, $V_{GS} = 0 V$, $T_C = 0$ mA, Referenced to 25	150°C				
cient Gate Voltage Drain Current o Body Leakage Current CS	I _D = 1 V _{DS} = V _{DS} =	0 mA, Referenced to 28		000	-	-	V
Gate Voltage Drain Current o Body Leakage Current CS	V _{DS} =	$480 \text{ V} \text{ V}_{CS} = 0 \text{ V}$	50	-	0.67	-	V/ºC
o Body Leakage Current	-			-	-	1	μA
cs	Vaa -	$V_{DS} = 480 \text{ V}, V_{GS} = 0 \text{ V}, T_{C} = 125^{\circ}\text{C}$		-	-	-	10 ^µ
	VGS -	= ±20 V, V _{DS} = 0 V		-	-	±100	nA
Threshold Voltage							
	V _{GS} =	· V _{DS} , I _D = 250 μA		2.5	-	3.5	V
Drain to Source On Resistant	ce V _{GS} =	= 10 V, I _D = 39 A		-	36	41	mΩ
rd Transconductance	V _{DS} =	20 V, I _D = 39 A		-	71	-	S
teristics							
Capacitance				-	10300	13700	pF
			-	1	355	475	pF
	f = 1 N	VIHZ	F	-	4	6	pF
Output Capacitance		380 V, V _{GS} = 0 V, f = 1	MHz	-	187	-	pF
ffective Output Capacitance				-	735	-	pF
				-	285	380	nC
			-	-	45	-	nC
o Drain "Miller" Charge	00		(Note 4)	-	105	-	nC
Equivalent Series Resistance		f = 1 MHz		-	1.2	-	Ω
cteristics							
					50	110	ns
,	V _{DD} =	V _{DD} = 380 V, I _D = 39 A,					ns
	V _{GS} =	10 V, R_{G}^{-} = 4.7 Ω	_		320	650	ns
		(Note 4)		-	85	180	ns
ode Characteristics	l.						
	ce Diode Fr	orward Current		-		77	A
				_	-		A
				-	-		V
				-	590	-	ns
se Recovery Charge			-	-	18	-	μC
	ive Output Capacitance Gate Charge at 10V to Source Gate Charge to Drain "Miller" Charge alent Series Resistance acteristics On Delay Time Off Delay Time Off Fall Time ode Characteristics num Continuous Drain to Source num Pulsed Drain to Source D to Source Diode Forward Volt se Recovery Time se Recovery Charge	Capacitance $V_{DS} = f = 1 M$ it Capacitance $f = 1 M$ rse Transfer Capacitance $V_{DS} = f = 1 M$ it Capacitance $V_{DS} = f = 1 M$ Gate Charge at 10V $V_{DS} = f = 1 M$ it o Source Gate Charge $V_{GS} = f = 1 M$ alent Series Resistance $f = 1 M$ acteristics $f = 1 M$ On Delay Time $V_{DD} = f = 0 M$ On Delay Time $V_{GS} = 0 M$ Off Delay Time $V_{GS} = 0 M$ Off Fall Time V_{GS} num Continuous Drain to Source Diode Forward M to Source Diode Forward Voltage V_{GS} se Recovery Time V_{GS} se Recovery Charge dI_{F}/c dth limited by maximum junction temperature. $rtig T_J = 25^{\circ}C$. s, $V_{DD} \leq 380V$, starting $T_J = 25^{\circ}C$. $s_{DS} = 0 M$	Capacitance at Capacitance $V_{DS} = 100 \text{ V}, \text{ V}_{GS} = 0 \text{ V},$ f = 1 MHzrse Transfer Capacitance $V_{DS} = 380 \text{ V}, \text{ V}_{GS} = 0 \text{ V}, \text{ f = 1}$ MHzive Output Capacitance $V_{DS} = 380 \text{ V}, \text{ V}_{GS} = 0 \text{ V}, \text{ f = 1}$ ive Output Capacitanceive Output Capacitance $V_{DS} = 0 \text{ V to } 480 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$ f = 1 MHzGate Charge at 10V $V_{DS} = 380 \text{ V}, \text{ I}_{D} = 39 \text{ A},$ $V_{GS} = 10 \text{ V}$ to Source Gate Charge alent Series Resistancef = 1 MHzacteristicsf = 1 MHzOn Delay Time Off Delay Time $V_{DD} = 380 \text{ V}, \text{ I}_{D} = 39 \text{ A},$ $V_{GS} = 10 \text{ V}, \text{ R}_{G} = 4.7 \Omega$ Off Fall TimeOde Characteristicsnum Continuous Drain to Source Diode Forward Current to Source Diode Forward Voltagev_{GS} = 0 V, I_{SD} = 39 \text{ A}, se Recovery Timev_{GS} = 0 V, I_{SD} = 39 \text{ A}, dI _F /dt = 100 A/µsdth limited by maximum junction temperature. rting T_J = 25°C.s, $V_{DD} \leq 380V$, starting T_J = 25°C.	Capacitance $V_{DS} = 100 \text{ V}, \text{ V}_{GS} = 0 \text{ V},$ It Capacitancef = 1 MHzrse Transfer Capacitance $V_{DS} = 380 \text{ V}, \text{ V}_{GS} = 0 \text{ V}, \text{ f = 1 MHz}$ ive Output Capacitance $V_{DS} = 380 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$ Gate Charge at 10V $V_{DS} = 380 \text{ V}, \text{ I}_D = 39 \text{ A},$ to Source Gate Charge $V_{GS} = 10 \text{ V}$ to Drain "Miller" Charge $V_{GS} = 10 \text{ V}$ alent Series Resistancef = 1 MHzOn Delay TimeOn Delay Time $V_{DD} = 380 \text{ V}, \text{ I}_D = 39 \text{ A},$ Off Delay Time $V_{CS} = 10 \text{ V}, \text{ R}_G = 4.7 \Omega$ Off Fall Time $V_{GS} = 0 \text{ V}, \text{ I}_{SD} = 39 \text{ A},$ ode Characteristics $V_{GS} = 0 \text{ V}, \text{ I}_{SD} = 39 \text{ A},$ num Continuous Drain to Source Diode Forward Currentnum Pulsed Drain to Source Diode Forward Currentto Source Diode Forward Voltagese Recovery Time $V_{GS} = 0 \text{ V}, \text{ I}_{SD} = 39 \text{ A},$ se Recovery Chargedth limited by maximum junction temperature.rtring T_J = 25°C.	Capacitance tt Capacitance $V_{DS} = 100 \text{ V}, \text{ V}_{GS} = 0 \text{ V},$ f = 1 MHz-rise Transfer Capacitance $V_{DS} = 380 \text{ V}, \text{ V}_{GS} = 0 \text{ V}, \text{ f = 1 MHz}-it CapacitanceV_{DS} = 380 \text{ V}, \text{ V}_{GS} = 0 \text{ V}, \text{ f = 1 MHz}-ive Output CapacitanceV_{DS} = 0 \text{ V to } 480 \text{ V}, \text{ V}_{GS} = 0 \text{ V}-Gate Charge at 10VV_{DS} = 380 \text{ V}, \text{ I}_D = 39 \text{ A},-to Source Gate ChargeV_{GS} = 10 \text{ V}-to Source Gate ChargeV_{GS} = 10 \text{ V}-to Drain "Miller" Charge(Note 4)-alent Series Resistancef = 1 MHz-On Delay TimeV_{DD} = 380 \text{ V}, \text{ I}_D = 39 \text{ A},-Off Delay TimeV_{DD} = 380 \text{ V}, \text{ I}_D = 39 \text{ A},-Off Fall TimeV_{DS} = 10 \text{ V}, \text{ R}_G = 4.7 \Omega-Off Fall TimeV_{GS} = 0 \text{ V}, \text{ I}_{SD} = 39 \text{ A},-num Continuous Drain to Source Diode Forward Current-num Pulsed Drain to Source Diode Forward Current-to Source Diode Forward VoltageV_{GS} = 0 \text{ V}, \text{ I}_{SD} = 39 \text{ A},-se Recovery TimeV_{GS} = 0 \text{ V}, \text{ I}_{SD} = 39 \text{ A},-se Recovery ChargedI_F/dt = 100 \text{ A}/\mu \text{s},-dth limited by maximum junction temperature$	Capacitance tt Capacitance $V_{DS} = 100 \text{ V}, \text{ V}_{GS} = 0 \text{ V},$ f = 1 MHz-10300 -it Capacitance $V_{DS} = 100 \text{ V}, \text{ V}_{GS} = 0 \text{ V},$ f = 1 MHz-355 4it Capacitance $V_{DS} = 380 \text{ V}, \text{ V}_{GS} = 0 \text{ V},$ f = 1 MHz-187ive Output Capacitance $V_{DS} = 380 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$ -735Gate Charge at 10V $V_{DS} = 380 \text{ V}, \text{ I}_{D} = 39 \text{ A},$ $V_{GS} = 10 \text{ V}$ -285to Source Gate Charge $V_{CS} = 10 \text{ V}$ $V_{CS} = 10 \text{ V}$ -105alent Series Resistancef = 1 MHz-1.2 Acteristics Dn Delay Time $V_{DD} = 380 \text{ V}, \text{ I}_{D} = 39 \text{ A},$ $V_{GS} = 10 \text{ V}, \text{ R}_{G} = 4.7 \Omega$ -50Off Delay Time $V_{DS} = 380 \text{ V}, \text{ I}_{D} = 39 \text{ A},$ $V_{GS} = 10 \text{ V}, \text{ R}_{G} = 4.7 \Omega$ -50Off Fall Time $V_{DS} = 0 \text{ V}, \text{ I}_{SD} = 39 \text{ A},$ $V_{GS} = 0 \text{ V}, \text{ I}_{SD} = 39 \text{ A},$ $V_{GS} = 0 \text{ V}, \text{ I}_{SD} = 39 \text{ A},$ $V_{GS} = 0 \text{ V}, \text{ I}_{SD} = 39 \text{ A},$ $V_{GS} = 0 \text{ V}, \text{ I}_{SD} = 39 \text{ A},$ $V_{GS} = 0 \text{ V}, \text{ I}_{SD} = 39 \text{ A},$ $V_{GS} = 0 \text{ V}, \text{ I}_{SD} = 39 \text{ A},$ $V_{GS} = 0 \text{ V}, \text{ I}_{SD} = 39 \text{ A},$ $V_{GS} = 0 \text{ V}, \text{ I}_{SD} = 39 \text{ A},$ $V_{GS} = 0 \text{ V}, \text{ I}_{SD} = 39 \text{ A},$ $V_{GS} = 0 \text{ V}, \text{ I}_{SD} = 39 \text{ A},$ $V_{GS} = 0 \text{ V}, \text{ I}_{SD} = 39 \text{ A},$ $V_{GS} = 0 \text{ V}, \text{ I}_{SD} = 39 \text{ A},$ $V_{GS} = 0 \text{ V}, \text{ I}_{SD} = 39 \text{ A},$ $V_{GS} = 0 \text{ V}, \text{ I}_{SD} = 39 \text{ A},$ $V_{GS} = 0 \text{ V}, \text{ I}_{SD} = 39 \text{ A},$ $V_{GS} = 0 \text{ V}, \text{ I}_{SD} = 39 \text{ A},$ $V_{GS} = 0 \text{ V}, $	Capacitance $V_{DS} = 100 \text{ V}, \text{ V}_{GS} = 0 \text{ V},$ - 10300 13700 it Capacitance f = 1 MHz - 355 475 isse Transfer Capacitance V_{DS} = 380 V, V_{GS} = 0 V, f = 1 MHz - 187 - ive Output Capacitance V_{DS} = 380 V, V_{GS} = 0 V - 735 - Gate Charge at 10V V_{DS} = 380 V, I_D = 39 A, - 285 380 to Source Gate Charge V_{GS} = 10 V - 45 - to Drain "Miller" Charge (Note 4) - 105 - alent Series Resistance f = 1 MHz - 1.2 - acteristics - 100 - 320 650 Dn Delay Time V_{DD} = 380 V, I_D = 39 A, - 50 110 Off Delay Time V_{GS} = 10 V, R_G = 4.7 \Omega - 320 650 Off Fall Time V_{GS} = 0 V, I_{SD} = 39 A, - - 1.2 num Continuous Drain to Source Diode Forward Current - - 77 num P

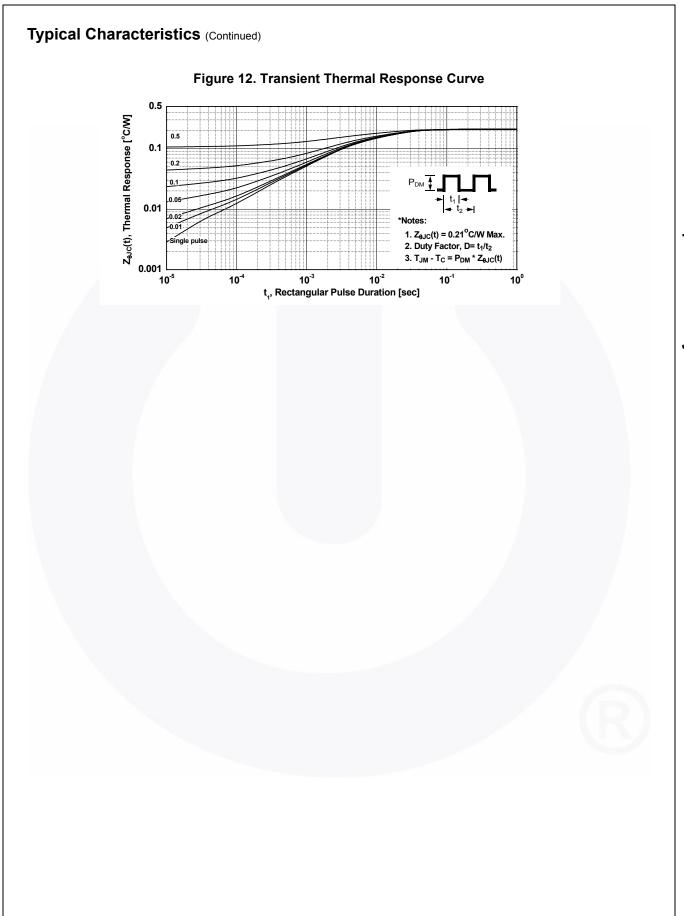
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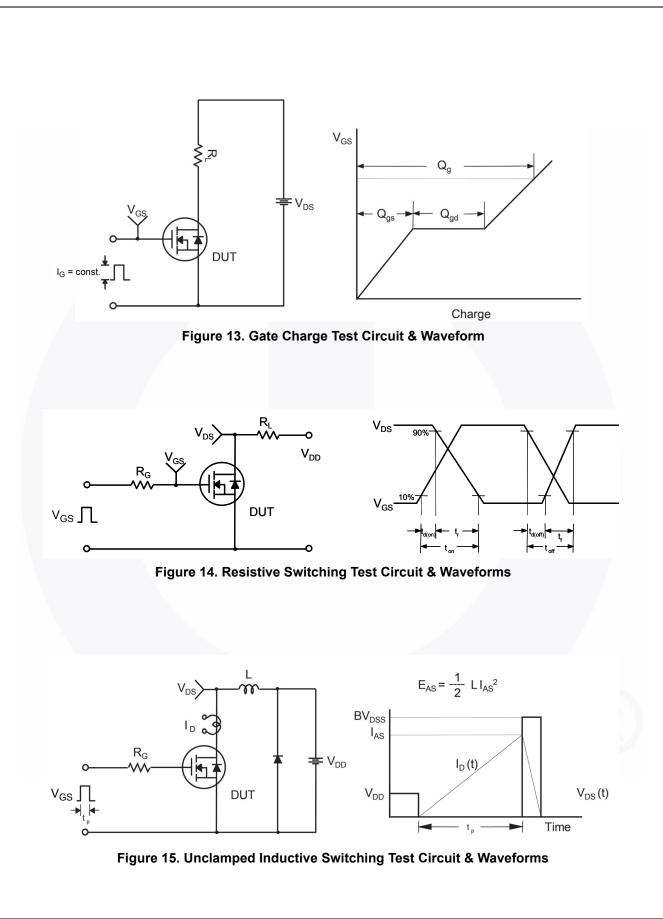


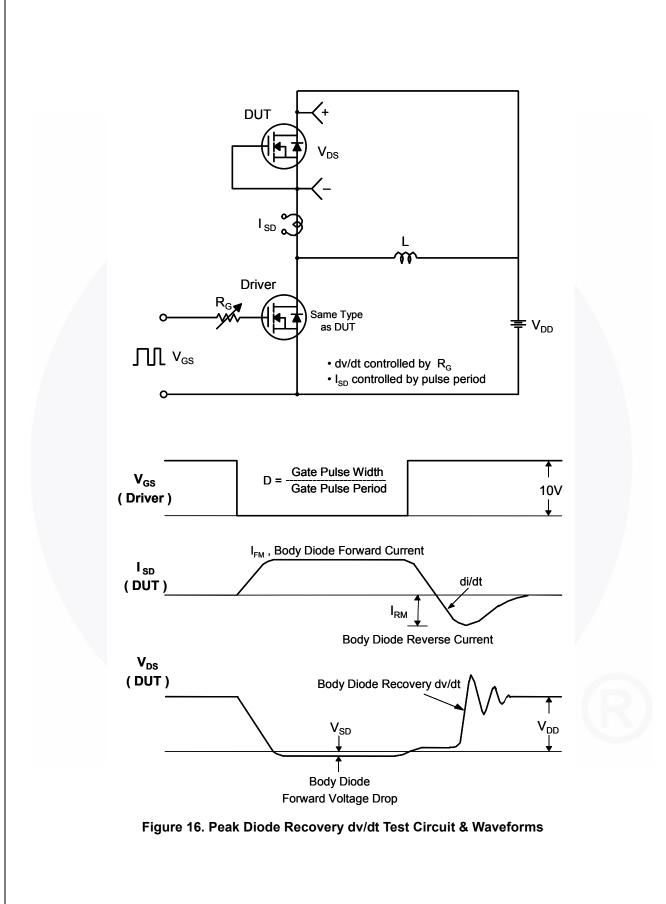


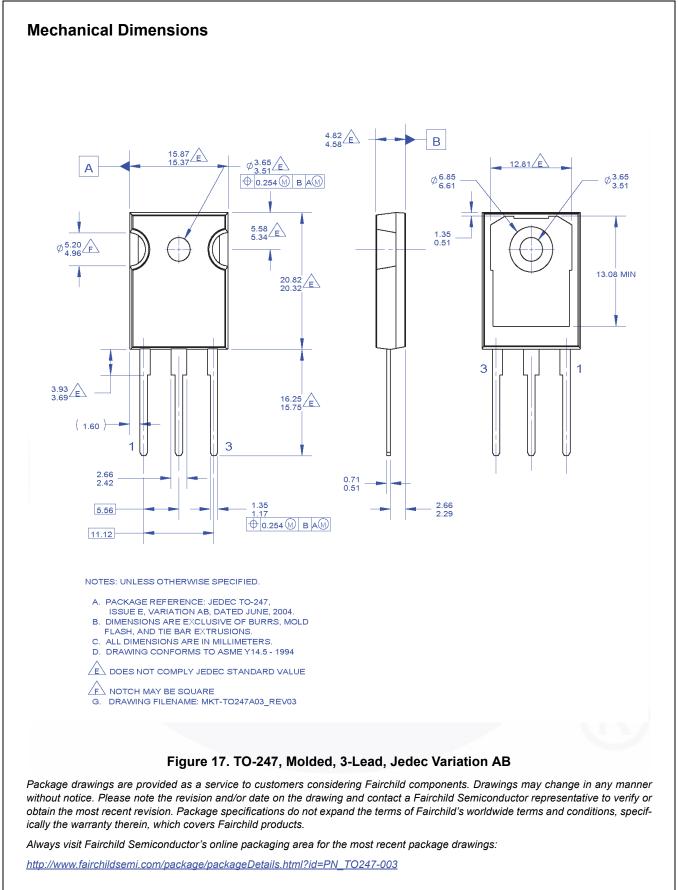
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